

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number BC850C-Q Part Description												
									Nexperia DHAM Small Signal Bipolar Transistor					
									SMD package					
		Test Conditions	Duration	# Lots	# Quantity	# Rejects								
			TEST											
			Pre- and Post-Stress											
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below								
		JESD22-A113 Bake Tamb = 125 °C	24 hours											
	PC	Soak Tamb = 123 °C, RH = 85%	168 hours											
# A1	Preconditioning	Reflow soldering	3 cycles	1674	70490	0								
		MIL-STD-750-1												
	HTRB	M1039 Method A												
		Tj = Tjmax, Vr = 100% of max. datasheet												
# B1	Bias	reverse voltage	1000 hours	415	18680	0								
	тс	JESD22-A104												
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	343	15360	0								
# 84			1000 Cycles	343	15500	0								
	UHAST	JESD22-A118												
# A3 <b>or</b>	Unbiased HAST	Tamb = 130 °C, RH = 85 %	06 1	362	15920	0								
		JESD22-A102	- 96 hours	302	15920	U								
	AC	Tamb = 121 °C, RH = 100 %												
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)												
		JESD22-A101												
	H3TRB High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of												
# A2 alt		rated reverse voltage <sup>[1]</sup>	1000 hours	343	15360	0								
# AZ ait	,	MIL-STD-750 Method 1037	1000 110013	343	15500	0								
	IOL	ton = toff, devices powered to insure $\Delta T_j$ =												
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	343	15360	0								
	RSH	JESD22-A111												
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	283	8490	0								
# C10	SD Solderability	1-STD-002		214	6420	0								
# C10	Solderability	J-STD-002		214	6420	0								

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia	Small Signal Bipolar				
DHAM	Transistor	18680	0	0,23	4,40E+09

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